



**International Conference on Solid-State
and Integrated Circuit Technology**
Nov. 1-4, 2010
InterContinental, Pudong
Shanghai, China
<http://www.icsict2010.com>

Invitation Letter

Dear Prof. Ker, Ming Dou

On behalf of the Technical Program Committee of ICSICT'2010 Conference, I am very pleased to invite you to give an invited talk on the technical session. It will be our honor to have your participation, and we hope to rely on your help to make the conference a success.

The ICSICT'2010, or the 10th International Conference on Solid State and Integrated Circuit Technology, will be held Nov.1-4, 2010 in Shanghai, China, just after the Shanghai World EXPO. It is the largest conference on integrated circuits and microelectronics technologies held in China every other year, to provide an international forum for the discussion of recent advances and future prospect in solid-state and integrated circuit technology as well as IC design. More information can be found at the web sites: <http://www.icsict2010.com>.

We sincerely hope that you will accept our invitation. Please reply by March 28, 2010, by filling out and return the attached reply form.

Best Regards,
Ting-Ao Tang

A handwritten signature in black ink, reading 'Ting-Ao Tang'.

Co-Chair of TPC of ICSICT 2010
Professor/Fudan University

March 17, 2010

On-Chip ESD Detection Circuit for System-Level ESD Protection Design

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Outline

- Introduction
- System-Level ESD Test
- ESD Detection Circuit
- Simulations
- Experimental Results
- Hardware/Firmware System Co-Design
- Conclusions

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